ON Semiconductor®

Test Procedure for the NCP456RFCCT2GEVB Evaluation Board

1. Connect strap between IN and Vbias
2. Connect 3.2 V between IN and GND
3. Check Vout = 0
4. Set EN = 2V
5. Check Vout = Vin
6. Set EN = 0V
7. Check Vout decreases down to GND
8. Disconnect Vin